

CL74AUP1G126 Single Bus Buffer Gate With 3-State Output

General Description

The single buffer is designed for 1.65-V to 5.5-V VCC operation.

The CL74AUP1G126 device is a single line driver with a 3-state output. The output is disabled when the output-enable input is low.

The CL74AUP1G126 device is available in a variety of packages, including the ultra-small DFN body size of 1 mm × 1 mm.

Ordering Information

Part Number	Package	
CL74AUP1G126	SOT-23-5	
	SOT-25	
	SOT-353	
	SOT-553	
	DFN1X1-4L	

Features

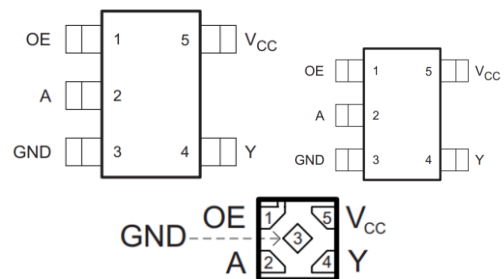
- Available in the Ultra Small DFN1X1
- Inputs Accept Voltages 0.8V to 3.6 V
- Max Tpd of 4.7 ns at 3.3 V
- Low Static-Consumption, 0.9-μA Max I_{CC}
- Low Noise Overshoot and Undershoot < 10% of V_{CC}
- Input-Disable Feature Allows Floating Input Conditions
- Ioff Supports Live Insertion, Partial-Power-Down Mode, and Back-Drive Protection
- Input Hysteresis Allows Slow Input Transition and Better Switching Noise Immunity at Input (V_{hys} = 250mV Typical 3.3V)
- 3.6V I/O Tolerant to Support Mixed-Mode Signal Operation
- Suitable for Point-to-Point Applications

- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- ESD Protection Exceeds JESD 22
 - 2000-V Human-Body Model (A114-A)
 - 1000-V Charged-Device Model (C101)

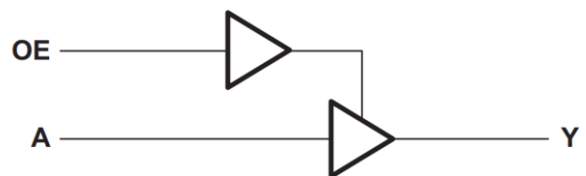
Applications

- audio Dock: Portable
- BluRay™ Players and Home Theaters
- Personal Digital Assistant (PDA)
- Power: Telecom/Server AC/DC Supply: Single Controller: Analog and Digital
- Solid-State Drive (SSD): Client and Enterprise
- TV: LCD/Digital and High-Definition (HDTV)
- Tablet: Enterprise
- Wireless Headsets, Keyboards and Mice

Pin Configuration



Simplified Schematic



Pin Name	Pin No.	Pin Function
\overline{OE}	1	Input
A	2	Input
GND	3	Ground
Y	4	Output
VCC	5	Power pin

Absolute Maximum Ratings (Note1)

- V_{CC} ----- -0.5V to +4.6V
- V_I ----- -0.5V to +4.6V
- V_O (Voltage range applied to any output in the high-impedance or power-off state)----- -0.3V to $V_{CC}+0.3V$
- V_O (Voltage range applied to any output in the high or slow state)----- -0.3V to $V_{CC}+0.3V$
- Input clamp current ----- -50mA
- Output clamp current ----- -50mA
- Continuous output current ----- $\pm 20mA$
- Storage Temperature ----- $-65^{\circ}C$ to $150^{\circ}C$

Recommended Operating Conditions

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Supply voltage	V_{CC}	Operating	0.8		3.6	V
Input voltage	V_I		0		3.6	V
Output voltage	V_O		0		V_{CC}	V
High- level input voltage	V_{IH}	$V_{CC} = 0.8V$	V_{CC}			V
		$V_{CC} = 1.1V$ to $1.95V$	$0.65 \times V_{CC}$			
		$V_{CC} = 2.3V$ to $2.7V$	1.6			
		$V_{CC} = 3V$ to $3.6V$	2			
Low- level input voltage	V_{IL}	$V_{CC} = 0.8V$			0	V
		$V_{CC} = 1.1V$ to $1.95V$			$0.35 \times V_{CC}$	
		$V_{CC} = 2.3V$ to $2.7V$			0.7	
		$V_{CC} = 3V$ to $3.6V$			0.9	

High- level output current	I_{OH}	$V_{CC} = 0.8V$			-20	uA
		$V_{CC} = 1.1V$			-1.1	mA
		$V_{CC} = 1.4V$			-1.7	
		$V_{CC} = 1.65V$			-1.9	
		$V_{CC} = 2.3V$			-3.1	
		$V_{CC} = 3V$			-4	
Low- level output current	I_{OL}	$V_{CC} = 0.8V$			20	uA
		$V_{CC} = 1.1V$			1.1	mA
		$V_{CC} = 1.4V$			1.7	
		$V_{CC} = 1.65V$			1.9	
		$V_{CC} = 2.3V$			3.1	
		$V_{CC} = 3V$			4	
Input transition rise or fall rate	$\Delta T/\Delta V$	$V_{CC} = 0.8V$ to $3.6V$			200	ns/V
Operating temperature	T_A		-40		85	°C

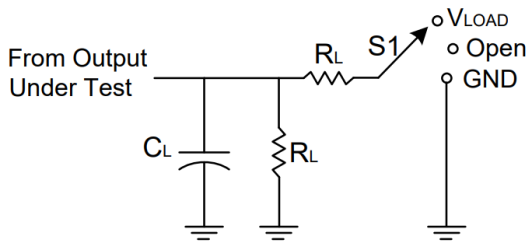
Electrical Characteristics

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
High- level output voltage	V_{OH}	$V_{CC} = 0.8\sim 3.6V, I_{OH} = -20\mu A$	$V_{CC}-0.1$			V
		$V_{CC} = 1.1V, I_{OH} = -1.1mA$	$0.75 \times V_{CC}$			
		$V_{CC} = 1.4V, I_{OH} = -1.7mA$	1.11			
		$V_{CC} = 1.65V, I_{OH} = -1.9mA$	1.32			
		$V_{CC} = 2.3V, I_{OH} = -2.3mA$	2.05			
		$V_{CC} = 2.3V, I_{OH} = -3.1mA$	1.9			
		$V_{CC} = 3V, I_{OH} = -2.7mA$	2.72			
		$V_{CC} = 3V, I_{OH} = -4mA$	2.6			
Low- level output voltage	V_{OL}	$V_{CC} = 0.8\sim 3.6V, I_{OL} = 20\mu A$			0.1	V
		$V_{CC} = 1.1V, I_{OL} = 1.1mA$			$0.3 \times V_{CC}$	
		$V_{CC} = 1.4V, I_{OL} = 1.7mA$			0.31	
		$V_{CC} = 1.65V, I_{OL} = 1.9mA$			0.31	
		$V_{CC} = 2.3V, I_{OL} = 2.3mA$			0.31	
		$V_{CC} = 2.3V, I_{OL} = 3.1mA$			0.44	
		$V_{CC} = 3V, I_{OL} = 2.7mA$			0.31	
		$V_{CC} = 3V, I_{OL} = 4mA$			0.44	
Input leakage current	I_I	$V_{IN} = 3.6V$ or GND, $V_{CC} = 0\sim 3.6V$			0.1	uA
Power off leakage current	I_{OFF}	V_I or $V_O = 0V$ to $3.6V, V_{CC} = 0V$			0.2	uA
Supply current	I_{CC}	$V_I = GND$ or (V_{CC} to $3.6V$), $I_{OUT} = 0$, $V_{CC} = 0.8\sim 3.6V$			0.5	uA
Additional supply current per input pin	ΔI_{CC}	$V_I = V_{CC} - 0.6V, I_{OUT} = 0$			40	uA

Switching Characteristics

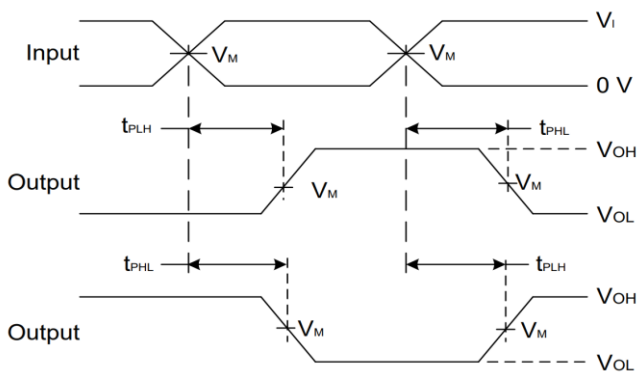
Parameter	From Input	To Output	Test Conditions	Min	Typ	Max	Units
T _{PD}	A	Y	V _{CC} = 0.8V		22.5		ns
			V _{CC} = 1.2V±0.1V,	5.8	9.3	15.1	
			V _{CC} = 1.5V±0.1V,	4.4	6.6	10.2	
			V _{CC} = 1.8V±0.15V	3.5	5.3	8.3	
			V _{CC} = 2.5V±0.2V	2.7	3.9	5.8	
			V _{CC} = 3.3V±0.3V	2.4	3.2	4.7	
T _{en}	OE	Y	V _{CC} = 0.8V		25.2		ns
			V _{CC} = 1.2V±0.1V,	7	11.3	18.1	
			V _{CC} = 1.5V±0.1V,	5.5	8.1	12.2	
			V _{CC} = 1.8V±0.15V	4.3	6.5	10.1	
			V _{CC} = 2.5V±0.2V	3.4	4.8	7.1	
			V _{CC} = 3.3V±0.3V	2.9	4.1	5.9	
T _{dis}	OE	Y	V _{CC} = 0.8V		14		ns
			V _{CC} = 1.2V±0.1V,	3.7	5.8	8.2	
			V _{CC} = 1.5V±0.1V,	5.5	3.9	5.9	
			V _{CC} = 1.8V±0.15V	3.3	4.5	6.6	
			V _{CC} = 2.5V±0.2V	2.3	3.2	4.3	
			V _{CC} = 3.3V±0.3V	2.4	4.8	6.2	

Parameter Measurement Information

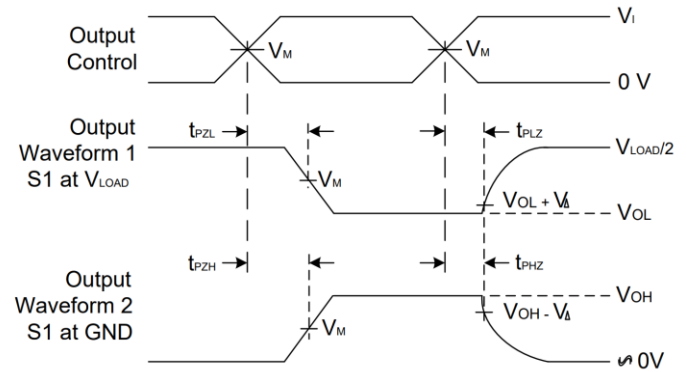


TEST	S1	RL
t_{PLH}/t_{PHL}	Open	1MΩ
t_{PLZ}/t_{PZL}	V _{LOAD}	5KΩ
t_{PHZ}/t_{PZH}	GND	5KΩ

V _{CC}	INPUTS		V _M	V _{LOAD}	C _L	V _Δ
	V _I	t _r /t _f				
0.8V	V _{CC}	≲3ns	V _{CC} /2	2 X V _{CC}	15pF	0.1V
1.2V±0.1V,	V _{CC}	≲3ns	V _{CC} /2	2 X V _{CC}	15pF	0.1V
1.5V±0.1V,	V _{CC}	≲3ns	V _{CC} /2	2 X V _{CC}	15pF	0.1V
1.8V±0.15V	V _{CC}	≲3ns	V _{CC} /2	2 X V _{CC}	15pF	0.15V
2.5V±0.2V	V _{CC}	≲3ns	V _{CC} /2	2 X V _{CC}	15pF	0.15V
3.3V±0.3V	V _{CC}	≲3ns	V _{CC} /2	2 X V _{CC}	15pF	0.3V



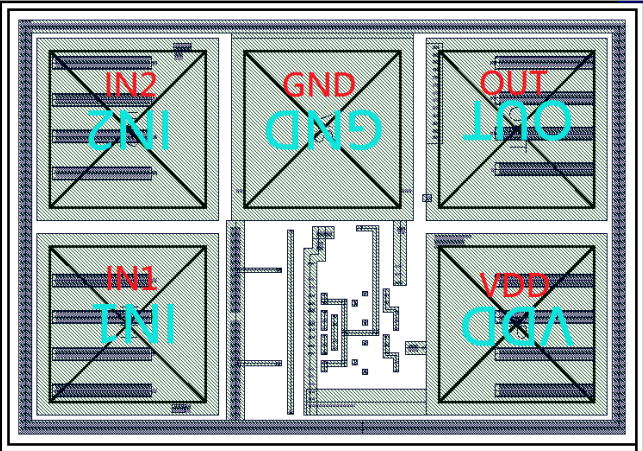
**Voltage Waveform Propagation Delay Times
Inverting and Non Inverting Outputs**



**Voltage Waveform Enable and Disable Times
Low- and High-Level Enabling**

- Notes:
- A. C_L includes probe and jig capacitance
 - B. All pulses and supplied at pulse repetition rate ≲10MHz
 - C. The Inputs are measured separately one transition per measurement
 - D. t_{PZL} and t_{PZH} are the same as t_{dis}
 - E. t_{PZL} and t_{PZH} are the same as t_{en}
 - F. t_{PLH} and t_{PHL} are the same as t_{pD}

PAD Location and Coordinates

PHYSICAL CHARACTERISTICS		UNIT	CHIP DRAWING
Wafer Size	200	mm	
Die Size (with S/L)	0.308 * 0.233	mm ²	
Scribe line width	60	um	
TOP Metal thickness	3	um	
Top Metallization	Al-Cu		
Wafer Thickness	726	um	
CUP (circuit under PAD) or not	YES		
Bonding Wire Diameter	20	um	

PAD NAME	PAD SIZE (μm ²)	Coordinate
IN 1	60*60	(49,49)
IN 2	60*60	(49,124)
GND	60*60	(124,124)
OUT (Y)	60*60	(199,124)
VDD	60*60	(199,49)

Bonding Diagram Example

